

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Kenneth P. Parker

Serial No.: Unknown

Examiner: Unknown

Filing Date: Unknown

Group Art Unit: Unk

Title: METHODS AND APPARATUS FOR MINIMIZING CURRENT SURGES DURING INTEGRATED CIRCUIT TESTING

5/IDS
E. Willis
10-30-01

COMMISSIONER FOR PATENTS
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)

under 37 CFR 1.97(c) together with either a:
 Statement under 37 CFR 1.97(e), or
 a \$180.00 fee under 37 CFR 1.17(p), or
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)

under 37 CFR 1.97 (d) together with a:
 Statement under 37 CFR 1.97(e), and
 a petition under 37 CFR 1.97(d)(2), and
 a \$130.00 petition fee set forth in 37 CFR 1.17(i).
(Filed after final action or notice of allowance, whichever occurs first, but before payment of the issue fee)

Please charge to Deposit Account 50-1078 the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account 50-1078 pursuant to 37 CFR 1.25.

Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Citation together with copies, of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

"Express Mail" label no. EL657274564US

Date of Deposit July 19, 2001

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Washington, D.C. 20231.

By 

Typed Name: Gregory W. Osterloft

Respectfully submitted,

Kenneth P. Parker

By 

Gregory W. Osterloft, Esq.

Attorney/Agent for Applicant(s)
Reg. No. 36,232

Date: July 19, 2001

Telephone No.: (970) 291-3200

jc971 U.S. PTO
09/908948
07/19/01


jc971 U.S. Pro
09/908948
07/19/01

FORM PTO-1449		ATTY. DOCKET NO. 10001121-1	SERIAL NO. 00/000,000
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		APPLICANT Kenneth P. Parker	
(Use several sheets if necessary)		FILING DATE Unknown	GROUP Unk

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	1A					
	1B					
	1C					
	1D					
	1E					
	1F					
	1G					
	1H					
	1I					
	1J					
	1K					

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION
							YES NO
	1L						
	1M						
	1N						
	1O						
	1P						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

1Q	"A Logic Design Structure for LSI Testability", E.B. Eichelberger and T.W. Williams, Proc. 14th Design Automation Conf. IEEE Pub. 77CH1216-1C, June 1977, pp 462-468
1R	"The Challenges of Design and Test for the World Wide Web", P. Gelsinger, Proc. International Test Conference, IEEE Pub. 99CH37034, Sept 1999, p 12
1S	"Enhancing Testability of Large; Scale Integrated Circuits Via Test Points and Additional Logic", M.J.Y. Williams and J.B. Angell, IEEE Trans. on Computers, Jan 1973, vol C-22, no.1, pp 46-60

EXAMINER DATE CONSIDERED

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO.	SERIAL NO.	
	10001121-1	00/000,000	
	APPLICANT	Kenneth P. Parker	
	FILING DATE	GROUP	Unknown

REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
2A					
2B					
2C					
2D					
2E					
2F					
2G					
2H					
2I					
2J					
2K					

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	TRANSLATION	
							YES	NO
	2L							
	2M							
	2N							
	2O							
	2P							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

2Q	"Design for Testability - A Survey", T.W. Williams and K.P. Parker, Proceedings of the IEEE, Jan. 1983, Vol 71, no. 1, pp 98-112
2R	"The Boundary Scan Cell", Texas Instruments, JTAG IEEE 1149.1/P1149.4 Tutorial, Sept. 1997, Tut.I-20, Tut II-24-26
2S	

EXAMINER	DATE CONSIDERED
----------	-----------------